



SMD Molding Power Inductor

Features

- 1, Soft saturation
- 2, High current, low DCR, high efficiency
- 3, High reliability.
- 4、100% Lead(Pb)-Free and RoHS compliant.
- 5. Operating temperature -40°C~+125°C (Including self temperature rise)

Applications

- 1, Note PC power system, incl. IMVP-6
- 2, DC/DC converter
- 3, Pad, Smart phone.
- 4. Portable gaming devices, Smart wear, Wi-Fi module.
- 5, Notebooks, VR, AR
- 6, LCD displays, HDDs, DVCs, DSCs, etc
- 7. Baseband power supply, Amplifier, Power management, Module power supply, Camera power manageme.

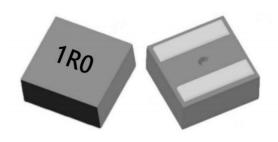
Lead Free Part Numbering

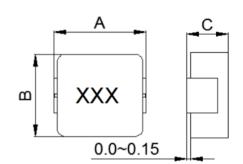
SLO 0412 T 1R0 M S T (1) (2) (3) (4) (5) (6) (7)

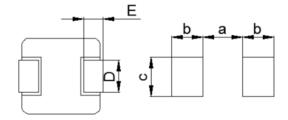
- (1) Series Type
- (2) Dimension: AXC
- (3) Material Code
- (4) Inductance: $1R0=1.0\mu H$;

 $2R2=2.2\mu H;$

- (5) Inductance Tolerance: M=±20%, Y=±30%
- (6) Company Code
- (7) Packaging: packed in embossed carrier tape







♦ Dimensions

Series	A±0.35(mm)	B±0.25(mm)	C±0.2(mm)	D ±0.3(mm)	E±0.3(mm)	а Тур	b Тур	с Тур
SLO0412T	4.5	4.2	1.0	3.4	0.8	2.2	1.5	2.5



SLO0412T Series

Specification

Deat New Lea	INDUCTANCE Lo(µ H)	DCR (m Ω) @25℃		Test a	Isat (A)	Irms (A)
Part Number		Max.	Тур.	condition	Тур.	Тур.
SLO0412T Series						
SLO0412TR47MTT	0.47	21	19	100KHz/0.1V	6.8	6.0
SLO0412TR68MTT	0.68	36	32	100KHz/0.1V	6.0	4.7
SLO0412T1R0MTT	1.0	47	43	100KHz/0.1V	5.5	4.5
SLO0412T1R5MTT	1.5	75	68	100KHz/0.1V	4.0	3.25
SLO0412T2R2MTT	2.2	85	79.3	100KHz/0.1V	3.0	2.75
SLO0412T3R3MTT	3.3	160	145	100KHz/0.1V	2.7	2.0
SLO0412T4R7MTT	4.7	200	175	100KHz/0.1V	2.2	1.8

NOTES:

- 1. Test frequency: L: 100KHz /0.1V;
- 2. All test in 25 °C temperature.
- 3.Testing Instrument:L:HP4285A,CH11025,CH3302,CH1320,CH1320S LCR METER / Rdc:CH16502, MICRO OHMMETER.
- 4. Heating Rating Current (Irms) will cause the coil temperature rise of 40°C approximately (Δt);
- 5. Saturation Current (Isat) will cause L0 to drop 30% approximately.
- 6.The part temperature (ambient + temp rise) should not exceed 125 °C under the worst case operating condition. Circuit design, component,PCB trace size and thickness airflow and other cooling provisions all could affect the part temperature. Part temperature should be verified in the end application.
- 7. Special inquiries besides the above common used types can be met on your requirement.n.



DCR Test



SLO0412T Series

♦ Reliability Test

Mechanical Relia	bility				
Item	Specification and Requirement	Test Method			
Terminal Strength	No removal or split of the termination or other defects shall occur.	 Solder the inductor to the testing jig (glass epoxy board shown in Fing.6.1-1) using eutectic solder. Then apply a force in the direction of the arrow. 10N force. Keep time: 5±2s 			
High Temperature	No visible mechanical damage. Inductance change: Within ±10%	1) Storage Temperature :125+/-5 2) Duration : 96 ±4 Hours 3) Recovery : then measured at room ambient temperature after placing 24 hours.			
Low Temperature	No visible mechanical damage Inductance change: Within ±10%	1) Temperature and time: -40±5 2) Duration: 96±4 hours 3) TRecovery: then measured at room ambient temperature after placing 24 hours.			
Vibration test	No visible mechanical damage. Inductance change: Within ±10%	1) Frequency range:10HZ~55HZ~10HZ 2) Amplitude:1.5mm p-p 3) Direction:X,Y,Z 4) Time:1 minute/cycle,2hours per axis			
High Temperature Storage Tested	No visible mechanical damage. Inductance change: Within ±10%	1)Storage Temperature :60+/-2℃ 2) Relative Humidity :90-95% 3) Duration : 96 ±4 Hours 4)Recovery : then measured at room ambient temperature after placing 24 hours.			
Resistance to Soldering Heat	1. No visible mechanical damage. 2. Inductance change: Within ±10% 260°C Peak 260°C max 217°C Max Ramp Down Rate=3°C/sec 200°C 150°C Max Ramp Down Rate=9°C/sec 60~90sec. Time 25°C to Peak =8 min max 5°C 80°C Time 25°C to Peak =8 min max	1) Re-flowing Profile: Please refer to Fig.6.6-1 2) Test board thickness: 1.0mm 3) Test board material: glass epoxy resin 4) The chip shall be stabilized at normal condition for 1~2 hours before measuring			
Thermal Shock	1. No visible mechanical damage. 2. Inductance change: Within ±10% 125°C 30 min. 30 min. Temperature 40°C 20sec. (max.)	 Temperature and time: -40±3 for 30±3 min→105 for 30±3min, please refer to Fig.6.7-1. Transforming interval: Max,3 minute Tested cycle: 100 cycles The chip shall be stabilized at normal condition for 1~2 hours before measuring 			